

EMB-900M

Compact Board. Intel(R) Pentium(R) 4 CPU 3.20GHz(200x16.0)

Thermal Image Analysis Report

Report No: 05E080021

Release Date: JUL 29, 2005

2005/07/29
Issue Stamp

Wenyuan Yang
Manager

YY Lin
Test Engineer

Thermal Image Analysis

I . Model Name :EMB-900M-A0.2

II . Description: ASS'Y.EMB-900M.Rev.A0.2
(BIOS Rev: 0.g for 18Bit LVDS (05/19/2005))

III . Date: Jul 29, 2005

IV. Measure Site: AAEON QE Dept.

V. Issued by : YY Lin

VI.Equipment:

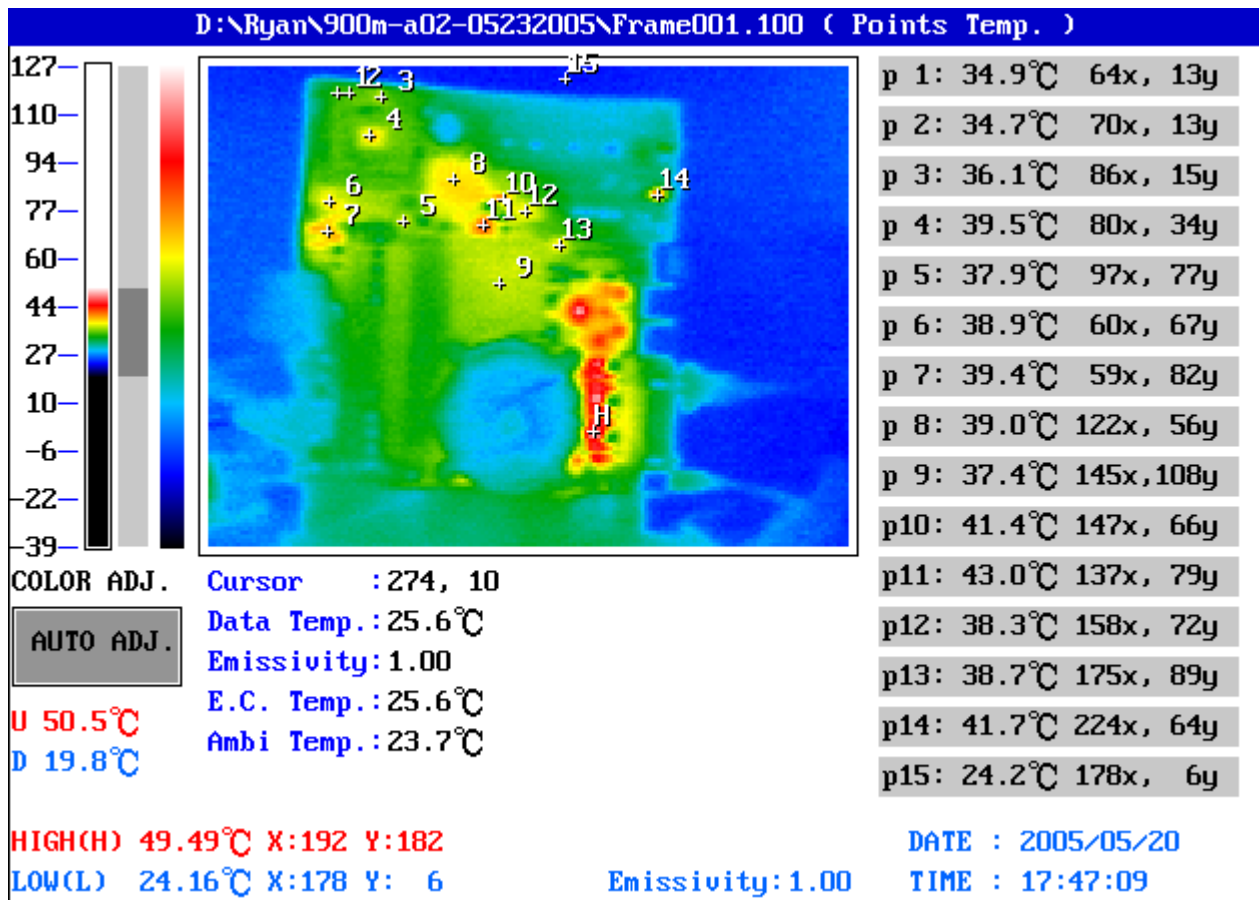
1. TVS-100 series by NIPPON AVIONICS CO., LTD.

VII. Simulation Environment:

- Temperature: Component Side (1) : 24.2 °C
Component Side (2) : 24.2 °C
Solder Side (3) : 25.0 °C
- CPU: Intel(R) Pentium(R) 4 CPU 3.20GHz(200x16.0)
- RAM-DDR II 1: KINGMAX/512MB/DDR2-533/Chipset : ELPIDA E5108AB-5C-E/ R2-2004004
- RAM-DDR II 2: KINGMAX/1GB/DDR2-533/Chipset : ELPIDA E5108AB-5C-E/R2-2004002
- RAM-DDR II 3: KINGMAX/512MB/DDR2-533/Chipset : ELPIDA E5108AB-5C-E/ R2-2004003
- RAM-DDR II 4: KINGMAX/1GB/DDR2-533/Chipset : ELPIDA E5108AB-5C-E/R2-2004001
- Application Software: Run HCT (9.5)System Stress Test under Win2000 Professional+SP4
- Take Picture Time: After Power on 2 hours.

Temperature Profile Test:

Component Side (1) :



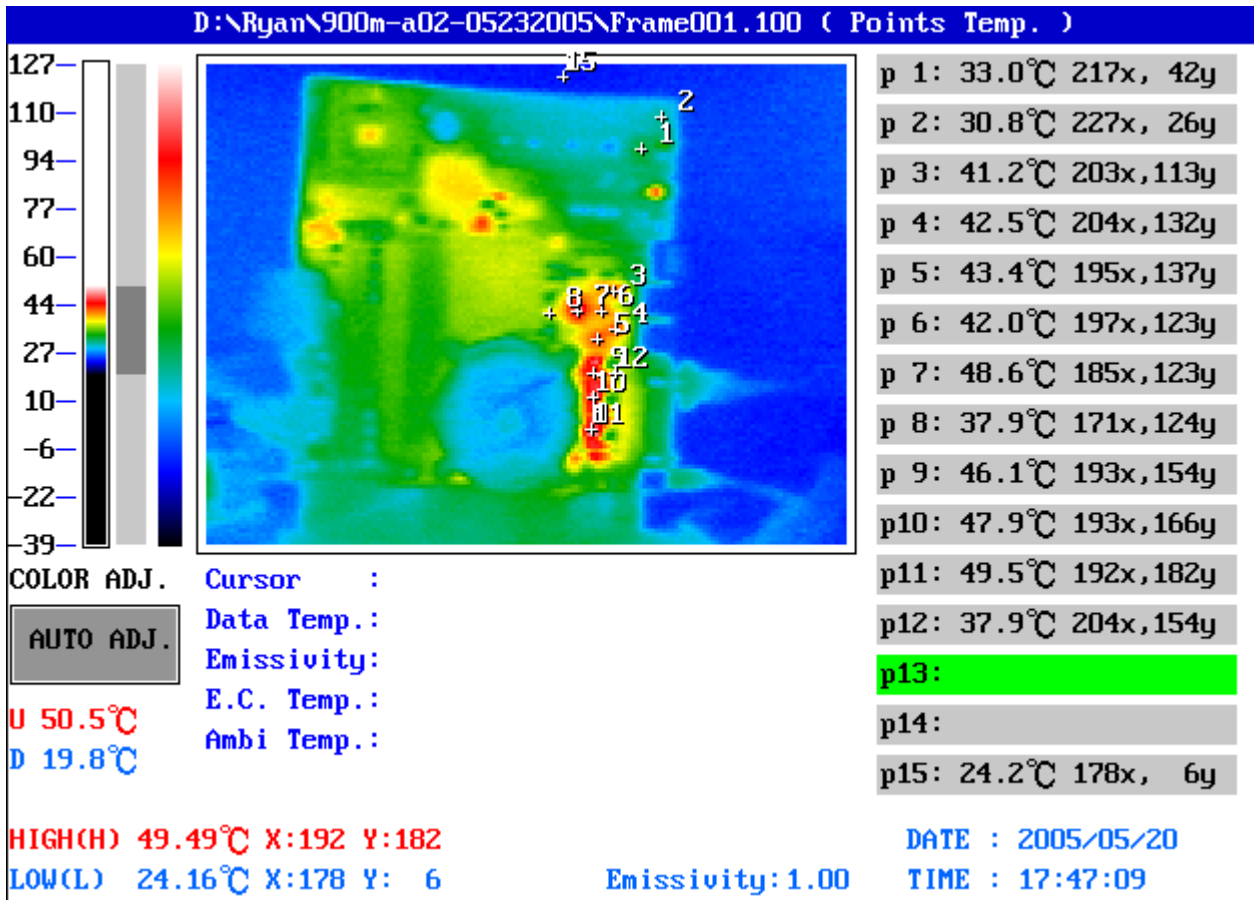
Point	Position	Describe	Tc	Tm (25°C)	Tm (60°C)	Note
1	U37	IC.SMD.SSOP RS232 Driver ESD 15KV.AD.ADM213EARS	-70~115°C	34.9°C	70.7°C	
2	U35	IC.SMD.SO8.RS-485 Transceiver.Analog.ADM485JR	-70~115°C	34.7°C	70.5°C	
3	U32	IC.SMD SO.14Pin.PHILIPS.74LVC06AD	-70~115°C	36.1°C	71.9°C	
4	U31	IC.SMD.QFP128P Super I/O.ITE.IT8712F-A/IX	-30~100°C	39.5°C	75.3°C	
5	U30	IC.SMD.QFN 28P.Power Controller.for Dual Channel DDR.Intersil.ISL6537CR	-30~100°C	37.9°C	73.7°C	
6	L14	COIL.2uH.DIP Wire Size1.0mm.18 材 3wire*6.5TS 20~30Amp. 高創.C6018-10C06YDP	-25~85°C	38.9°C	74.7°C	
7	L15	COIL.1uH.DIP WIRE SIZE 1.0mm.高創.C5026-10A06YDP	-25~85°C	39.4°C	75.2°C	
8	U29	IC.SMD.Chipset ICH6.INTEL.FW82801FB SL7AG	-40~85°C	39.0°C	74.8°C	
9	U26	IC.SMD.Chipset GRANTSDALE 915-GV.INTEL.RG82915GV-SL7W5	-55~150°C	37.4°C	73.2°C	
10	Q18	PWR.SMD.TO-252.N-Channel Power 25V 60A MOSFET.APEC.AP70T03H	-30~150°C	41.4°C	77.2°C	
11	Q19	PWR.SMD.TO-252.N-Channel Power 25V 60A MOSFET.APEC.AP70T03H	-30~150°C	43.0°C	78.8°C	
12	U24	IC.SMD.QFP128P Super I/O.ITE.IT8712F-A/IX	-30~100°C	38.3°C	74.1°C	
13	U22	IC.SMD LQFP.64P.LVDS Transmitter.CHRONTEL.CH7308	-40~125°C	38.7°C	74.5°C	
14	U2	(TF)IC.SMD.LQFP 48P.7.1 Channel High Definition.Audio Codec.REALTEK.ALC880-VH-LF	-30~100°C	41.7°C	77.5°C	
15		Ambient Temperature		24.2°C		

1. Operation Temperature (°C):
 $T_c(\text{Case temp.}) = T_a(\text{Ambient Temp.}) + /-30^\circ\text{C} = T_j(\text{Junction Temp.}) - /+25^\circ\text{C}$

Note: The description in red states which temperature is over the specification of the device.

Temperature Profile Test:

Component Side (2) :



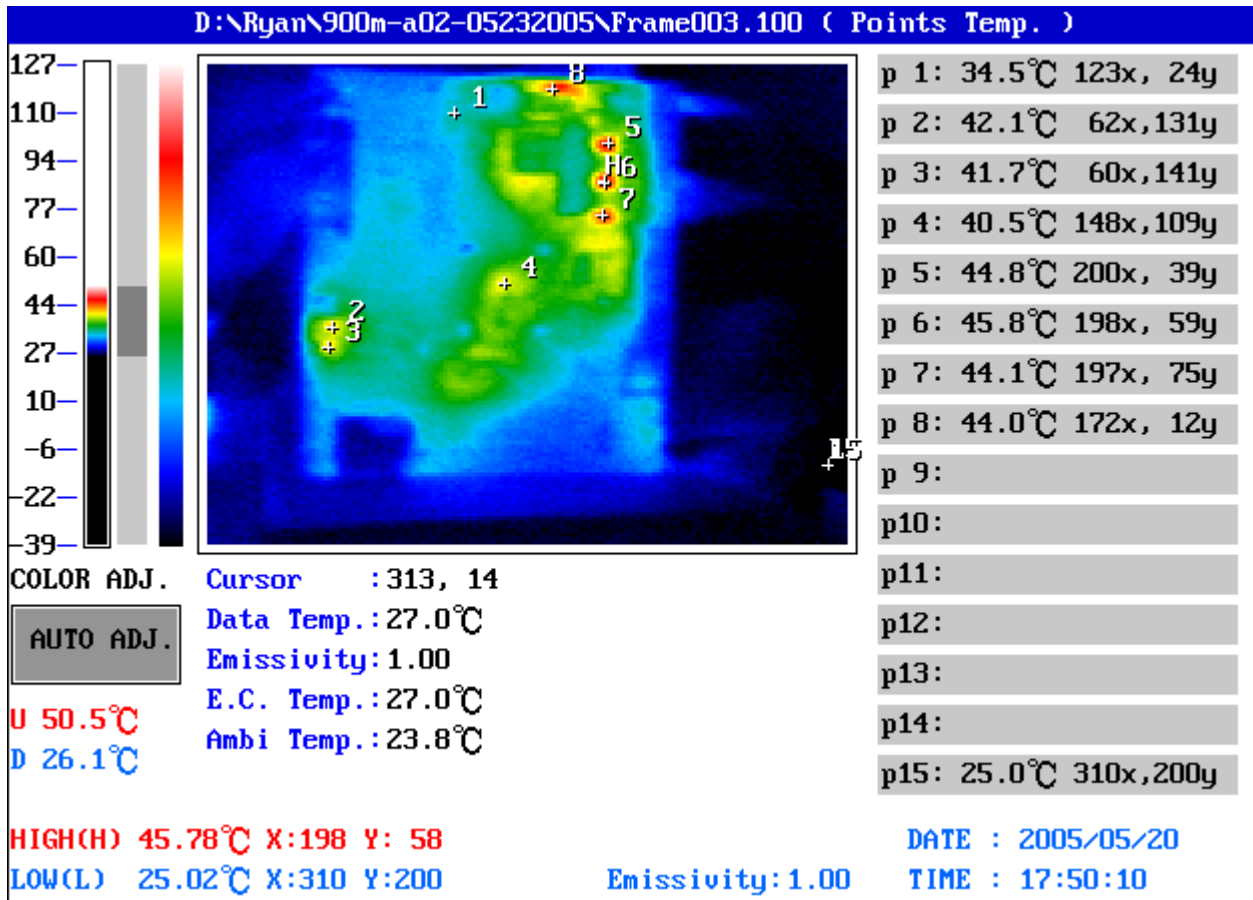
Point	Position	Describe	Tc	Tm (25°C)	Tm (60°C)	Note
1	U6	IC.SMD PQFP 128P.PCI to ISA Bridge Chip.Winbond.W83628F	-30~100°C	33.0°C	68.8°C	
2	U1	IC.SMD LQFP 48P.PCI to ISA Bridge Chip.Winbond.W83629D	-30~100°C	30.8°C	65.8°C	
3	U12	IC.SMD QFN 64P.PCI-E GigaBit Ethernet Chipset.Marvell.88E8053-A2-NNC	-55~125°C	41.2°C	77°C	
4	U13	IC.SMD QFN 64P.PCI-E GigaBit Ethernet Chipset.Marvell.88E8053-A2-NNC	-55~125°C	42.5°C	78.3°C	
5	U17	IC.SMD LQFP.48P.DVI Transmitter.CHRONTEL.CH7307C-DE	-45~125°C	43.4°C	79.2°C	
6	Q7	PNP.SMD.SOT-223.1Amp.ON.BCP69T1	-45~125°C	42.0°C	77.8°C	
7	U18	C.SMD.SSOP56.Clock Generator.ICS.ICS954101DF	-30~100°C	48.6°C	84.4°C	
8	Q15	PWR.SMD.TO-252.N-Channel Power 25V 60A MOSFET.APEC.AP70T03H	-25~150°C	37.9°C	73.7°C	
9	L2	COIL.0.9uH.DIP Wire Size 1.5mm.EE-1213-0R9P 30Amp.震元.303-00080	-70~115°C	46.1°C	81.9°C	
10	L3	COIL.0.9uH.DIP Wire Size 1.5mm.EE-1213-0R9P 30Amp.震元.303-00080	-70~115°C	47.9°C	83.7°C	
11	L4	COIL.0.9uH.DIP Wire Size 1.5mm.EE-1213-0R9P 30Amp.震元.303-00080	-70~115°C	49.5°C	85.3°C	
12	Q56	PWR.DIP.DPAK CASE.369D(TO-251).N-Channel MOSFET.ON SEMI.NTD60N02	-30~150°C	37.9°C	73.7°C	
13						
14						
15		Ambient Temperature		24.2°C		

1. Operation Temperature (°C):
 $T_c(\text{Case temp.}) = T_a(\text{Ambient Temp.}) + /-30^\circ\text{C} = T_j(\text{Junction Temp.}) - /+25^\circ\text{C}$

Note: The description in red states which temperature is over the specification of the device.

Temperature Profile Test:

Solder Side (3) :



Point	Position	Describe	Tc	Tm (25°C)	Tm (60°C)	Note
1	U48	IC.SMD.SOIC 28Pin PWM Controller.Intersil.ISL6556BCB	-35~125°C	34.5°C	70.3°C	
2	Q53	PWR.SMD.TO-252.N-Channel Power 30V 55A MOSFET. APEC.AP60N03H	-30~125°C	42.1°C	77.9°C	
3	Q54	PWR.SMD.TO-252.N-Channel Power 25V 60A MOSFET.APEC.AP70T03H	-30~125°C	41.7°C	77.5°C	
4	U26	IC.SMD.Chipset GRANTSDALE 915-GV.INTEL.RG82915GV-SL7W5	-55~150°C	40.5°C	76.3°C	
5	L4	COIL.0.9uH.DIP Wire Size 1.5mm.EE-1213-0R9P 30Amp.震元.303-00080	-70~115°C	44.8°C	80.6°C	
6	L3	COIL.0.9uH.DIP Wire Size 1.5mm.EE-1213-0R9P 30Amp.震元.303-00080	-70~115°C	45.8°C	81.6°C	
7	L2	COIL.0.9uH.DIP Wire Size 1.5mm.EE-1213-0R9P 30Amp.震元.303-00080	-70~115°C	44.1°C	79.9°C	
8	L11	COIL.0.9uH.DIP Wire Size 1.5mm.EE-1213-0R9P 30Amp.震元.303-00080	-70~115°C	44.0°C	75.8°C	
9						
10						
11						
12						
13						
14						
15		Ambient Temperature		25.0°C		

1. Operation Temperature (°C):
 $T_c(\text{Case temp.}) = T_a(\text{Ambient Temp.}) - 30^\circ\text{C} = T_j(\text{Junction Temp.}) - 25^\circ\text{C}$

Note: The description in red states which temperature is over the specification of the device.